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Application No. <u>101005,689</u>	Prepared by <u>N.H.</u>	Tracking Number <u>05884744</u>	
Examiner-GAU <u>Zarnela - 2829</u>	Date <u>1-29-04</u>	Week Date <u>01/05/04</u>	
	No. of queries <u>1</u>	IFW	

## JACKET

- |                      |                        |                    |                    |
|----------------------|------------------------|--------------------|--------------------|
| a. Serial No.        | f. Foreign Priority    | k. Print Claim(s)  | <u>p. PTO-1449</u> |
| b. Applicant(s)      | g. Disclaimer          | l. Print Fig.      | q. PTOL-85b        |
| c. Continuing Data   | h. Microfiche Appendix | m. Searched Column | r. Abstract        |
| d. PCT               | i. Title               | n. PTO-270/328     | s. Sheets/Figs     |
| e. Domestic Priority | j. Claims Allowed      | o. PTO-892         | t. Other           |

## SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

## CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

## MESSAGE

PTO-1449: Please either initial or line through citations. Copy provided for reference.

Thank you

initials N.H.

## RESPONSE

initials

**INFORMATION DISCLOSURE CITATION**  
(37 CFR 1.97)

Application Number  
Filing Date  
First Named Inventor **Rutten**  
Group Art Unit  
Examiner Name  
Attorney Docket **US 018180**

11036 U.S. PTO  
10/005689  
11/08/01

U.S. PATENT DOCUMENTS							
Examiner's Initials	Cite No.	Patent Number	Date	Name	Class	Sub-Class	Filing Date, If Approp.
	AA	6,075,373	13 June 2000	Iino			
	AB	6,169,410 B1	2 January 2001	Grace et al.			
	AC	(copending application) "PRECONDITIONED INTEGRATED CIRCUIT FOR INTEGRATED CIRCUIT TESTING"		Rutten			(concurrent)
	AD						
	AE						
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS								
Examiner's Initials	Cite No.	Patent Number	Date	Country	Class	Sub-Class	Translation	
							Yes	No
	AI	EP 0 755 071 A2	18 July 1996	Europe				
	AJ							
	AK							
	AL							
	AM							

Examiner's Initials	Cite No.	Other (Include Author, Title, Date, Pertinent Pages, Etc.)
	AN	"Introducing WOW Technology", <a href="http://www.formfactor.com/about/wow/wow_pg2.html">http://www.formfactor.com/about/wow/wow_pg2.html</a>
	AO	"Introducing WOW Technology", <a href="http://www.formfactor.com/about/wow/wow_pg5.html">http://www.formfactor.com/about/wow/wow_pg5.html</a>
	AP	"Focus on FormFactor", THE FINAL TEST REPORT, Vol. 12, No. 09, September 2001, Ikonix Corp. P.O. Box 1938, Lafayette, CA 94549-1938
	AQ	"Flip-Chip Bonding on 6-um Pitch using Thin-Film Microspring Technology", Donald L. Smith et al., Xerox Palo Alto Research Center, Proceedings, 48 <sup>th</sup> Electronic Components and Technology Conference, IEEE, May 1998.
	AR	

Examiner	Date Considered
Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to the Applicant.	